

JCM37

BEST AVAILABLE COPY

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10001977	FILING DATE 12/05/2001	CLASS 438	SUBCLASS 1	GAU 2812	EXAMINER UP Perkins
**APPLICANTS: Tanimoto Hiroyoshi; Enda Toshiyuki;					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED: JAPAN 2001-313939 10/11/2001					
PG-PUB DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO			
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		216548US2			
Verified and Acknowledged Examiners's initials					
TITLE : Semiconductor device, method of manufacturing semiconductor device, and system for evaluating electrical characteristics of semiconductor device					
U.S. DEPT. OF COMM./PAT & TM, PTO-415L (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims
			Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING
Amount Due	Date Paid		Sheets Drwg. Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner
WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only			

FILED WITH

☐ DISK (CRF)

☐ CD-ROM

(Attached in pocket on right inside flap)